

Search Notes

Application/Control No.

10/726,834

Examiner

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Applicant(s)/Patent under
Reexamination

LEE, CHIOU-HAUN

Art Unit

3714

SEARCHED

Class	Subclass	Date	Examiner
463	9, 14	5/28/2007	SEJ
273	153R, 156	5/28/2007	SEJ
273	157R, 153 S	5/28/2007	SEJ
273	153J	5/28/2007	SEJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See Attached Search History		5/28/2007	SEJ

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Searched EAST USPAT, USPGPUB, EPO, JPO, and DERWENT databases.	5/28/2007	SEJ